Laser Beam Quality Metrics

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First rule of laser beam quality metrics:

Any attempt to reduce the behavior of a seven-dimensional* object to a single number inevitably results in loss of information.

^{*}three-amplitude, three-phase, and time

Introduction to the Series

Since its inception in 1989, the Tutorial Texts (TT) series has grown to cover many diverse fields of science and engineering. The initial idea for the series was to make material presented in SPIE short courses available to those who could not attend and to provide a reference text for those who could. Thus, many of the texts in this series are generated by augmenting course notes with descriptive text that further illuminates the subject. In this way, the TT becomes an excellent stand-alone reference that finds a much wider audience than only short course attendees.

Tutorial Texts have grown in popularity and in the scope of material covered since 1989. They no longer necessarily stem from short courses; rather, they are often generated independently by experts in the field. They are popular because they provide a ready reference to those wishing to learn about emerging technologies or the latest information within their field. The topics within the series have grown from the initial areas of geometrical optics, optical detectors, and image processing to include the emerging fields of nanotechnology, biomedical optics, fiber optics, and laser technologies. Authors contributing to the TT series are instructed to provide introductory material so that those new to the field may use the book as a starting point to get a basic grasp of the material. It is hoped that some readers may develop sufficient interest to take a short course by the author or pursue further research in more advanced books to delve deeper into the subject.

The books in this series are distinguished from other technical monographs and text-books in the way in which the material is presented. In keeping with the tutorial nature of the series, there is an emphasis on the use of graphical and illustrative material to better elucidate basic and advanced concepts. There is also heavy use of tabular reference data and numerous examples to further explain the concepts presented. The publishing time for the books is kept to a minimum so that the books will be as timely and up-to-date as possible. Furthermore, these introductory books are competitively priced compared to more traditional books on the same subject.

When a proposal for a text is received, each proposal is evaluated to determine the relevance of the proposed topic. This initial reviewing process has been very helpful to authors in identifying, early in the writing process, the need for additional material or other changes in approach that would serve to strengthen the text. Once a manuscript is completed, it is peer reviewed to ensure that chapters communicate accurately the essential ingredients of the science and technologies under discussion.

It is my goal to maintain the style and quality of books in the series and to further expand the topic areas to include new emerging fields as they become of interest to our reading audience.

James A. Harrington Rutgers University

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Preface

This book will help the reader to thread through the subtleties of laser beam quality analysis and requirements synthesis. Chapter 1 begins with a review of basic laser properties and moves to definitions and implications of the various standard beam quality metrics such as M^2 , power in the bucket, brightness, beam parameter product, and Strehl ratio. For those who are only interested in measuring Gaussian beams from commercial lasers, Chapter 1, Chapter 2 "What Your Laser Beam Analyzer Manual Didn't Tell You," and the first three sections of Chapter 6 "Cautionary Tales" will be sufficient. For the reader in more off-the-map areas such as unique lasers, unstable resonators, multikilowatt lasers, MOPAs, or requirements generation and development, a reading of the entire text is recommended.

The author got his start in laser metrics when assigned to align a parametric oscillator as a researcher fresh out of graduate school. After making the oscillator operational, he used a commercial beam profiler and discovered that it gave a number of either 1.3 or 7, sometimes alternating between the two in rapid succession. A perusal of the product manual added little light; everything of real interest was hidden behind the word *proprietary*. He put the commercial black box back on the shelf. Armed with a video capture card, digital camera, motion control stage, the ISO 11145:1999 standard, and LabVIEW, he built his own laser profiler, including automated M^2 measurement using both the camera and knife edge. In so doing, he made just about every mistake possible and came to understand how these metrics work.

This system was used internally for several years and then retired when research needs changed. It was not until a few years later—when several hundred-million-dollar-plus laser development programs ran into trouble over the issue of laser beam quality specifications—that he realized how lacking this basic information was in the directed-energy community. It turned out to be all too easy to purchase a laser system that met specification but would not accomplish the intended task. His first beam quality publication, "Appropriate measures and consistent standard for high energy laser beam quality" was published in the Summer 2006 edition of the *Journal of Directed Energy* and won several awards. Other papers expanded the body of practical beam quality literature and were developed into a laser beam quality course that has been a regular feature of several Directed Energy Professional Society (DEPS) conferences and has been taught at SPIE's Defense, Security, and Sensing Symposia. This text is an outgrowth of these short courses.

T. Sean Ross March 2013

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Abbreviations, Symbols, and Notation

0 index or subscript for reference beam or fundamental mode

2D two dimensional 3D three dimensional

a constant, aperture radius

A area
B brightness

BPP beam parameter product

BQ beam quality

speed of light in a vacuum, $\sim 2.99792 \times 10^8$ m/sec

CCD charge-coupled device CID charge-injection device C_n constant with index n

COIL chemical oxygen iodine laser

CW continuous wave

d differential operator. Infinitesimal change in the symbol that

follows

D second-moment diameter of the beam waist

DL diffraction limited, meaning that the beam is ideal in some sense transcendental number, 2.718281828..., the base of natural

logarithms

E energy \vec{E} , \mathbf{E} electric field error function

f frequency, focal length
 F fluence, energy per area
 ff subscript for far field
 FWHM full width at half maximum

G metric prefix meaning one billion

GHz Gigahertz, unit of bandwidth or frequency

GW gigawatt

HBQ horizontal beam quality (horizontal definition of power in the

bucket)

HeNe helium-neon

 $H_n[x]$ n^{th} Hermite polynomial HPIB horizontal power in the bucket HWHM half width at half maximum

 $HW1/e^2M$ half width at $1/e^2$ (13.5%) maximum

Hz hertz, unit of frequency

i subscript for Laguerre–Gaussian mode index

I irradiance, power per area

 I_{nm} irradiance due to the (n,m)th mode ISO International Standards Organization

i, j, k integer indices $\hat{i}, \hat{j}, \hat{k}$ unit vectors

j the imaginary number $\sqrt{-1}$ Joule, unit of energy

 J_n n^{th} ordinary Bessel function k metric prefix meaning 1000 k wavenumber = $2 \pi/\lambda$

 $k_i, k[x]$ knife-edge measurement at the i^{th} position, at the

x position

 k_{mp} wavenumber of $(m,p)^{\text{th}}$ mode $K_n[x]$ n^{th} modified Bessel function kW kilowatt, unit of power

L length

 L_c coherence length

 $L_p^m[x]$ (p,m)th associated Laguerre polynomial

ln natural logarithm function

m subscript for Laguerre–Gaussian mode index

mm millimeter, unit of length

 M, M^2 mode factor, mode factor squared. A common

measure of beam quality

MOPA master oscillator power amplifier

NFresnel numberNAnumerical apertureNDneutral density (filters)

Nd:YAG neodymium-doped yttrium aluminum garnet

NEAnoise equivalent aperturenfsubscript for near fieldNGGnon-Gaussian Gaussian

NIST National Institute of Standards and Technology

nm nanometer, unit of length

nsec nanosecond

OPA optical parametric amplifier
OPO optical parametric oscillator
P power, energy per time

 $_{\delta}^{\beta}$

PDF	probability density function
PIB	power in the bucket, usually refers to the curve of
	encircled power versus radius
q	complex beam radius
r	radial spatial variable
$ar{r}$	average radius
R	radius, radius of curvature
r_0	particular radius
rms	root mean square
S	Strehl ratio
SNR	signal-to-noise ratio
t	time
T_c	coherence time
и	electric field amplitude
u,U	integration variable
v,V	integration variable
V	waveguide V number
$ec{V}$	vector
VBQ	vertical beam quality (vertical definition of power
-	in the bucket)
V_i	<i>i</i> th vector component
VPIB	vertical power in the bucket
v[r]	variable aperture measurement
\mathcal{W}	beam radius
W	measured beam radius
w_0, W_0	beam radius of the fundamental mode
w[0], W[0]	beam waist
WFE	wavefront error
$\mathcal{W}[z]$	Lambert W function, the transcendental solution
	of $z = We^{W}$. Implemented in <i>Mathematica</i> [®] as
	ProductLog[z]. Returns real values from -1 to
	infinity for arguments ranging from $-1/e$ to
	infinity.
\hat{X}	unit vector
\bar{x},\bar{y}	average x, y
x, y, z, X, Y, Z	spatial variables
Yb:YLF	ytterbium-doped yttrium lithium fluoride
Z	zero noise level
Z_R	Rayleigh range
∞	infinity
α	constant
R	wayaguida propagation constant

waveguide propagation constant Dirac delta function

change in, or change of, the symbol that follows
grid spacing in the x direction
grid spacing in the y direction
bandwidth in wavelength
bandwidth in frequency
percent obscuration
vacuum permittivity 8.854×10^{-12} F/m (farad/meter)
angle
divergence angle of a reference beam of fundamental mode
divergence half angle
incident angle
reflected angle
transmitted angle
wavelength
wavelength divided by near-field aperture diameter.
Interpreted as the tangent of an angle. Common unit of
diffraction angle for a laser beam.
micron, unit of length
frequency
transcendental number, ratio of circumference of a circle to
diameter, 3.14159
variance
rms amplitude noise expressed as percent of peak
phase error
solid angle